

DOCKET NO: 265253US2PCT



IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF : DATE ALLOWED: 02/13/06
RYOJI SETAKA, ET AL. : EXAMINER: HOLLINGTON, J.M.
SERIAL NO: 10/522,537 :
FILED: JANUARY 27, 2005 : GROUP ART UNIT: 2829
FOR: ANISOTROPIC CONDUCTIVITY :
CONNECTOR, PROBE MEMBER,
WAFER INSPECTING DEVICE, AND
WAFER INSPECTING METHOD

AMENDMENT UNDER 37 CFR §1.312

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Notice of Allowance dated February 13, 2006, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 5 of this paper.